

<b>Notice of References Cited</b>	Application/Control No. 09/915,419	Applicant(s)/Patent Under Reexamination NAKAZAWA ET AL.	
	Examiner Jon Hadidi	Art Unit 2671	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0143622 A1	10-2002	Taliercio et al.	705/14
	B	US-2001/0018667	08-2001	Kim, Yang Shin	705/14
	C	US-6,227,974 B1	05-2001	Eilat et al.	463/40
	D	US-2003/0156134 A1	08-2003	Kim, Kyunam	345/753
	E	US-6,229,533 B1	05-2001	Farmer et al.	345/473
	F	US-2002/0089506 A1	07-2002	Templeman, James N.	345/473
	G	US-6,244,959 B1	06-2001	Miyamoto et al.	463/31
	H	US-6,448,970 B1	09-2002	Kajioka et al.	345/473
	I	US-5,524,195 A	06-1996	Clanton et al.	725/61
	J	US-2002/0171647 A1	11-2002	Sterchi et al.	345/473
	K	US-6,686,918 B1	02-2004	Cajolet et al.	345/473
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.